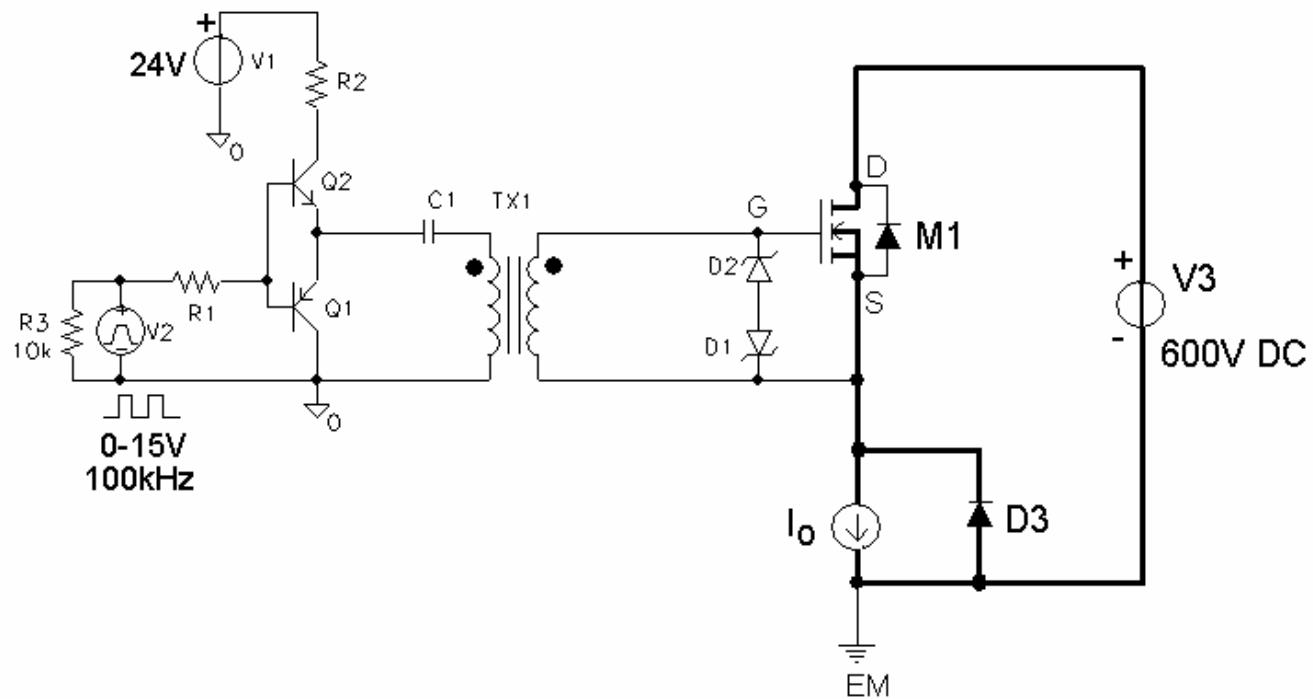


VISER-NET-SPECIJALISTIČKE STUDIJE

PREDMET: Upravljanje Elektroenergetskim Pretvaračima

DOMAĆI ZADATAK_02

Dimenzionisati elemente u pobudnom kolu MOSFET prekidača, koje je prikazano na slici. MOSFET M1 je IXFL 60N80P (proizvodnje IXYS) za 800V/40A. Tehnički podaci za tranzistor M1 su dati u PRILOGU-1. Struja opterećenja koju ovo kolo treba da prekida je $I_0 = 30A$. Iz naponskog izvora V2 se generišu pobudni naponski impulsi 0-15V prekidačke učestanosti 100kHz i promenljivog koeficijenta režima rada ("duty-cycle"). Pojačanja tranzistora Q1 i Q2 su $\beta = 200$, naponi baza-emitor u linearnom režimu su $V_{BE} = 0.6V$, a u stanju zasićenja su $V_{BES} = 0.7V$. Naponi kolektor-emiter u stanju zasićenja su $V_{CES} = 0.7V$. Podaci za impulsni transformator TX1 su dati u PRILOGU-2. Tehnički podaci za diodu D3 su dati u PRILOGU-3. Za projektovano kolo na slici odrediti minimalnu i maksimalnu srednju vrednost struje tranzistora M1, kao i opseg podešavanja snage na opterećenju. Procenti maksimalnu trenutnu vrednost struje tranzistora M1, kao i njegove prekidačke gubitke i gubitke u stanju vođenja.



PRILOG-1



PolarHV™ HiPerFET IXFL 60N80P Power MOSFET ISOPLUS264™

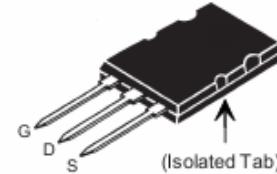
(Electrically Isolated Back Surface)

N-Channel Enhancement Mode
Avalanche Rated
Fast Intrinsic Diode

$V_{DSS} = 800$ V
 $I_{D25} = 40$ A
 $R_{DS(on)} \leq 150$ mΩ
 $t_{rr} \leq 250$ ns



ISOPLUS264™ (IXFL)



G = Gate D = Drain
S = Source

Symbol	Test Conditions	Maximum Ratings		
V_{DSS}	$T_J = 25^\circ C$ to $150^\circ C$	800		V
V_{DGR}	$T_J = 25^\circ C$ to $150^\circ C$; $R_{GS} = 1 M\Omega$	800		V
V_{GSS}	Continuous	± 30		V
V_{GSM}	Transient	± 40		V
I_{D25}	$T_C = 25^\circ C$	40		A
I_{DM}	$T_C = 25^\circ C$, pulse width limited by T_{JM}	150		A
I_{AR}	$T_C = 25^\circ C$	30		A
E_{AR}	$T_C = 25^\circ C$	100		mJ
E_{AS}	$T_C = 25^\circ C$	5		J
dv/dt	$I_S \leq I_{DM}$, $di/dt \leq 100$ A/μs, $V_{DD} \leq V_{DSS}$, $T_J \leq 150^\circ C$, $R_G = 2 \Omega$	20		V/ns
P_D	$T_C = 25^\circ C$	625		W
T_J		-55 ... +150		°C
T_{JM}		150		°C
T_{sg}		-55 ... +150		°C
T_L	1.6 mm (0.062 in.) from case for 10 s	300		°C
V_{ISOL}	50/60 Hz, RMS $I_{ISOL} \leq 1$ mA	t = 1 min t = 1 s	2500 3000	V~
F_c	Mounting force	28..150 / 6.4..30		N/lb
Weight		5		g

Symbol	Test Conditions ($T_J = 25^\circ C$, unless otherwise specified)	Characteristic Values		
		Min.	Typ.	Max.
BV_{DSS}	$V_{GS} = 0$ V, $I_D = 3$ mA	800		V
$V_{GS(th)}$	$V_{DS} = V_{GS}$, $I_D = 8$ mA	3.0	5.0	V
I_{GSS}	$V_{GS} = \pm 30$ V _{DC} , $V_{DS} = 0$		± 200	nA
I_{DSS}	$V_{DS} = V_{DSS}$ $V_{GS} = 0$ V		25 3000	μA
$R_{DS(on)}$	$V_{GS} = 10$ V, $I_D = I_T$, Note 1		150	mΩ

Features

- | International standard isolated package
- | UL recognized package
- | Silicon chip on Direct-Copper-Bond substrate
 - High power dissipation
 - Isolated mounting surface
 - 2500V electrical isolation
- | Unclamped Inductive Switching (UIS) rated
- | Low package inductance
 - easy to drive and to protect
- | Fast intrinsic diode

Advantages

- | Easy to mount
- | Space savings
- | High power density

Symbol	Test Conditions	Characteristic Values		
		($T_j = 25^\circ C$, unless otherwise specified)	Min.	Typ.
g_{fs}	$V_{DS} = 20 V; I_D = I_T$, Note 1	35	67	S
C_{iss}	$V_{GS} = 0 V, V_{DS} = 25 V, f = 1 \text{ MHz}$	18	nF	
		1200	pF	
		44	pF	
$t_{d(on)}$	$V_{GS} = 10 V, V_{DS} = 0.5 V_{DSS}, I_D = I_T$ $R_G = 1 \Omega$ (External)	36	ns	
		29	ns	
		110	ns	
		26	ns	
$Q_{g(on)}$	$V_{GS} = 10 V, V_{DS} = 0.5 V_{DSS}, I_D = I_T$	250	nC	
		90	nC	
		78	nC	
R_{thJC}			0.20	°C/W
R_{thCS}		0.13		°C/W

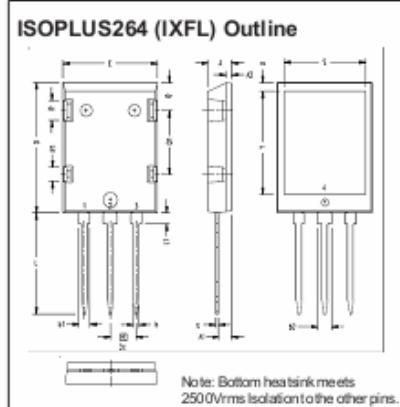
Source-Drain Diode

Characteristic Values
($T_j = 25^\circ C$, unless otherwise specified)

Symbol	Test Conditions	Characteristic Values		
		Min.	Typ.	Max.
I_s	$V_{GS} = 0 V$		60	A
I_{SM}	Repetitive		150	A
V_{SD}	$I_F = I_s, V_{GS} = 0 V$, Note 1		1.5	V
t_{rr}	$I_F = 25 A, -di/dt = 100 A/\mu s$		250	ns
			0.6	μC
I_{RM}	$V_R = 100 V$		6.0	A

Notes:

- Pulse test, $t \leq 300 \mu s$, duty cycle $d \leq 2\%$

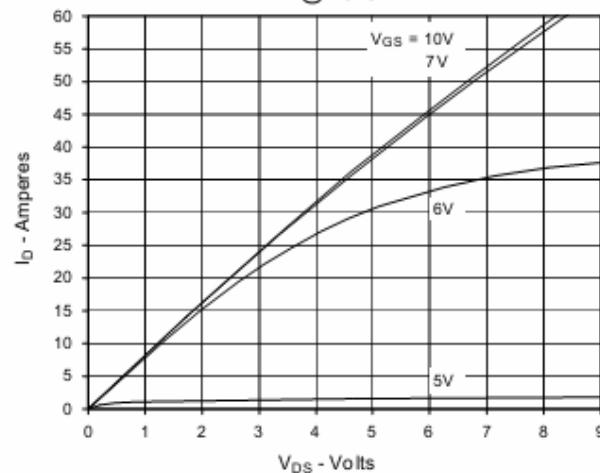
Test Current $I_T = 30 A$ 

Note: Bottom heatsink meets 2500Vrms isolation to the other pins.

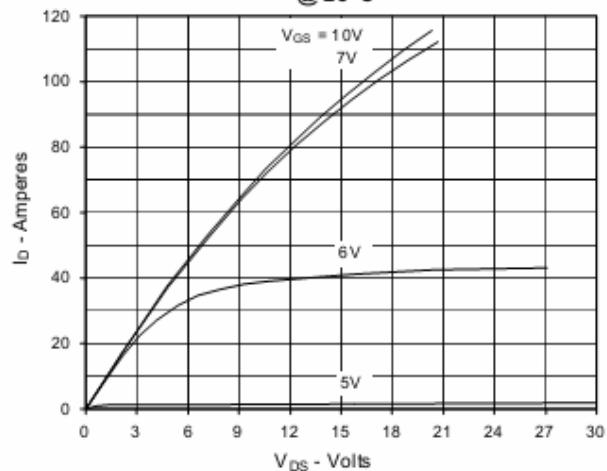
Sym	INCHES		MILLIMETERS	
	MIN	MAX	MIN	MAX
A	.190	.205	4.83	5.21
A1	.102	.118	2.59	3.00
A2	.046	.055	1.17	1.40
b	.045	.055	1.14	1.40
b1	.087	.102	2.21	2.59
b2	.111	.126	2.82	3.20
c	.020	.029	0.51	0.74
D	1.020	1.040	25.91	26.42
E	.770	.789	19.56	20.09
e	.215 BSC		5.46 BSC	
L	.780	.820	19.81	20.83
L1	.080	.103	2.03	2.59
Q	.210	.235	5.33	5.97
Q1	.490	.513	12.45	13.63
R	.150	.180	3.81	4.57
R1	.100	.130	2.54	3.30
S	.668	.690	16.97	17.53
T	.801	.821	20.34	20.85
U	.055	.080	1.45	1.93

Ref: IXYS CO0128R0

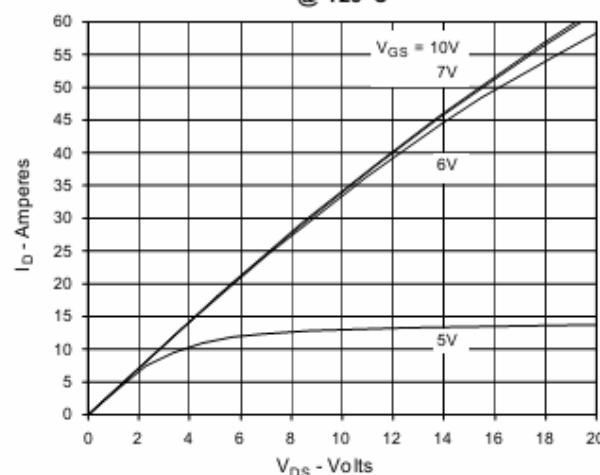
**Fig. 1. Output Characteristics
@ 25°C**



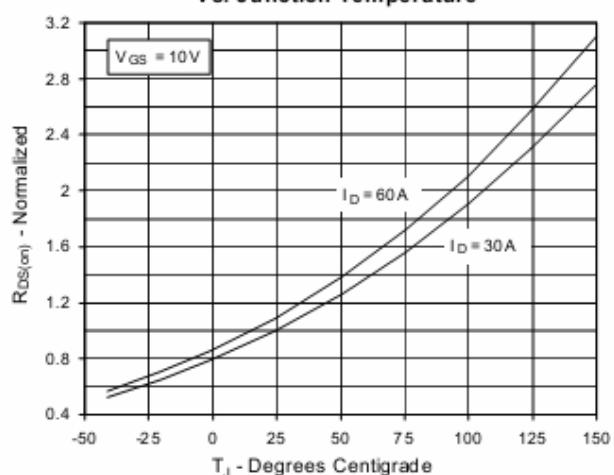
**Fig. 2. Extended Output Characteristics
@ 25°C**



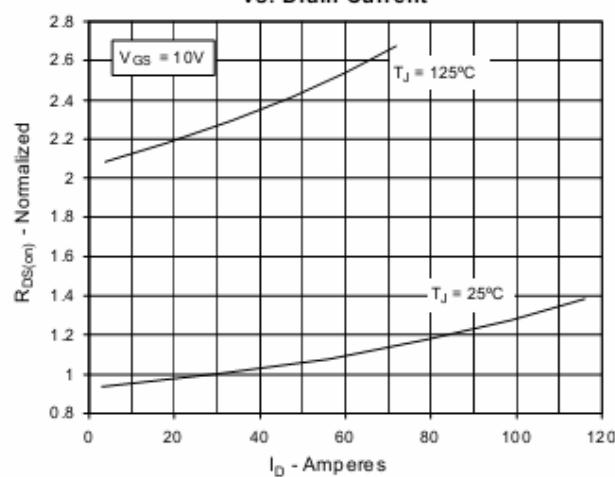
**Fig. 3. Output Characteristics
@ 125°C**



**Fig. 4. $R_{DS(on)}$ Normalized to $I_D = 30A$ Value
vs. Junction Temperature**



**Fig. 5. $R_{DS(on)}$ Normalized to $I_D = 30A$ Value
vs. Drain Current**



**Fig. 6. Maximum Drain Current vs.
Case Temperature**

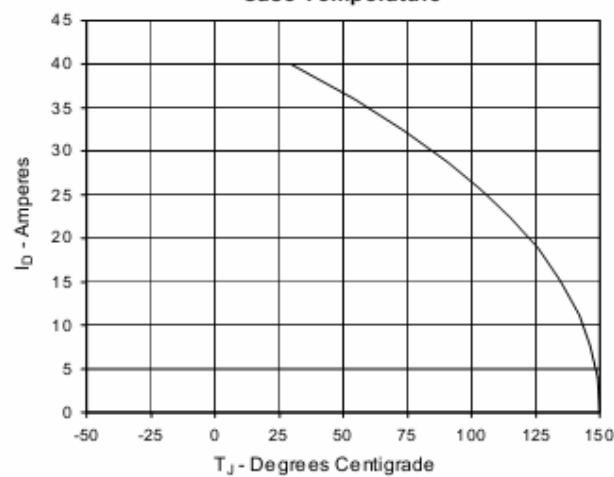
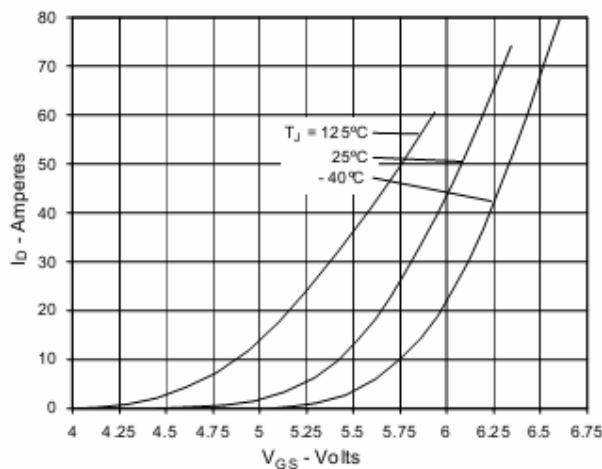
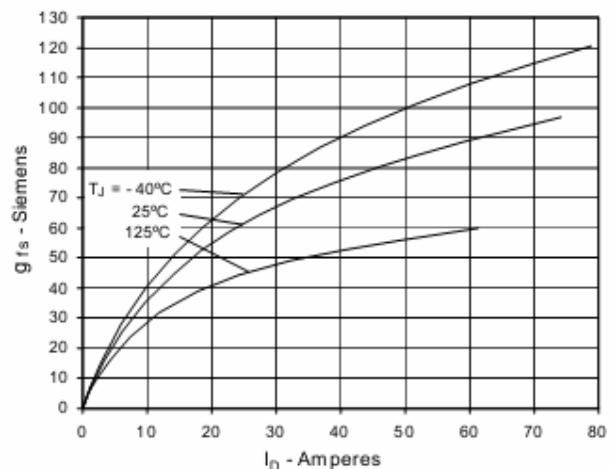
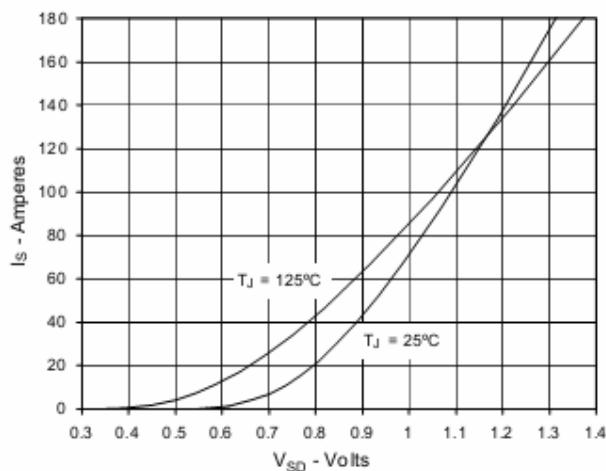
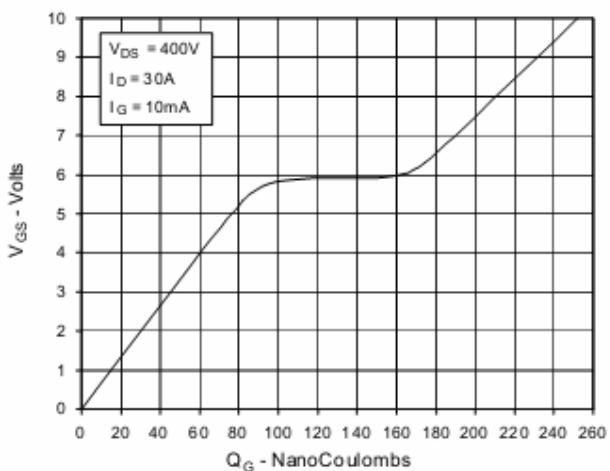
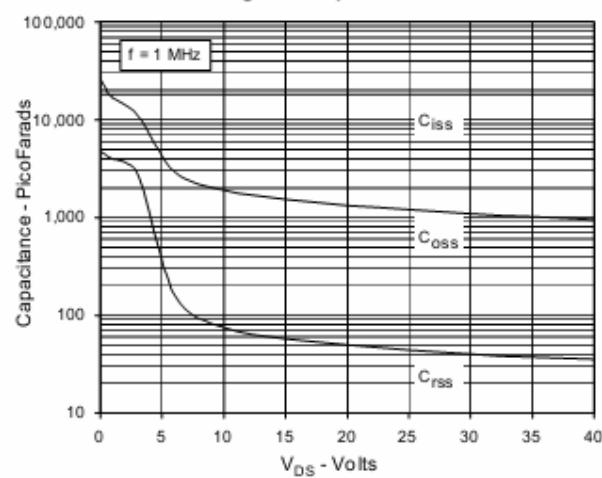
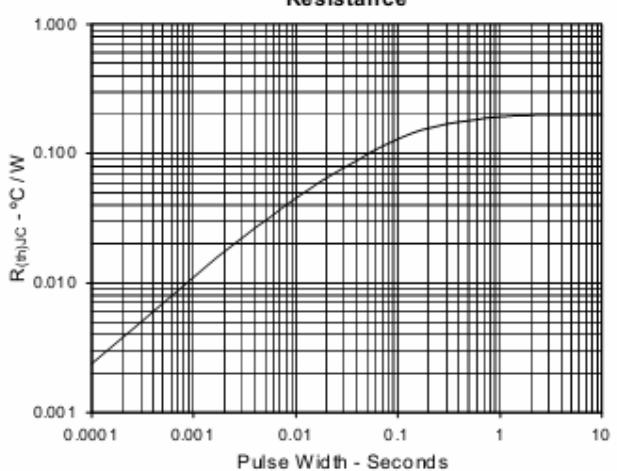


Fig. 7. Input Admittance

Fig. 8. Transconductance

Fig. 9. Forward Voltage Drop of Intrinsic Diode

Fig. 10. Gate Charge

Fig. 11. Capacitance

Fig. 12. Maximum Transient Thermal Resistance


PRILOG-2

MOSFET GATE DRIVE TRANSFORMERS



- International safety construction, VDE approved
 - 3750V_{RMS} gate to drive winding test
 - Useful operating frequency from 20kHz to 100kHz

Electrical Specifications @ 25°C — Operating Temperature 0°C to 70°C

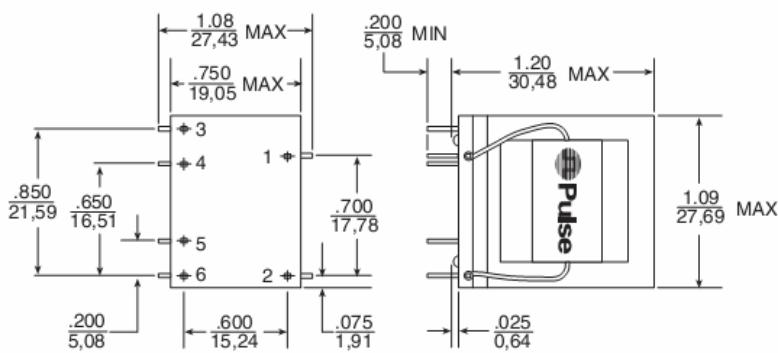
Part Number	Turns Ratio (±5%)	Inductance 1VRMS 1 kHz Term 1-2 (μ H MIN)	Leakage Inductance Term 1-2 (μ H MAX)	DCR Drive Winding (Ω MAX)	DCR Gate Winding (Ω MAX)	C_{WW} Drive To Gate (pf MAX)	C_{WW} Gate To Gate (pf MAX)	Typical Operating Frequency (kHz)
PE-63385NL	1:1	1500	4.0	0.40	0.75	50	NA	20-100
PE-63387NL*	1:1:1	1500	4.0	0.40	0.75	50	130	20-100
PE-63386NL	1:1.5	1500	4.0	0.40	2.50	50	NA	20-100
PE-63388NL	1:1.5:1.5	1500	4.0	0.40	2.50	50	130	20-100

***NOTE:** Also Available with a U-L B1 Insulation (1446C) system, tested to 4400Vrms for 1 minute as PE-68448NL.

Maximum Ratings				
Rating	Sym	PE-63385 PE-63386	PE-63387 PE-63388	Unit
Drive Excitation, Unipolar	E_{T_U} ⁶	200	320	V _μ s
Drive Excitation, Bipolar	E_{T_B} ⁶	400	640	V _μ s
Secondary RMS Current	I_{SR} ⁷	640	500	ma
Operating & Storage Temp.	T_{OP}, T_{STG}	105	105	°C

Dielectric Strength	
Test Between	RMS Test Volts 60Hz, 1 Minute Hold
Gate-Drive	3750
Gate-Gate	1500
Gate-Core	2000
Drive-Core	1750

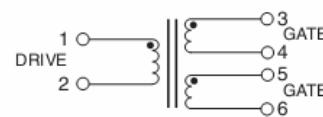
Mechanical



Schematics



PE-63385NL/PE-63386NL



PE-63387NI / PE-63388NI / PE-68448NI

NOTES: 1. Measured with secondaries shorted
2. Pins .025/0,64 square solderable
3. Unused pins not provided
4. Pin numbers not marked on part

- 5. Mounting header flammability rating: UL-94V0
- 6. At 2480 Gauss
- 7. At 200 CM/Amp

Dimensions: Inches
mm
Unless otherwise specified,
all tolerances are $\pm \frac{0.010}{\text{each}}$

PRILOG-3



1000V 40A
APT40DQ100B APT40DQ100S
APT40DQ100BG* APT40DQ100SG*

*G Denotes RoHS Compliant, Pb Free Terminal Finish.

ULTRAFAST SOFT RECOVERY RECTIFIER DIODE

PRODUCT APPLICATIONS

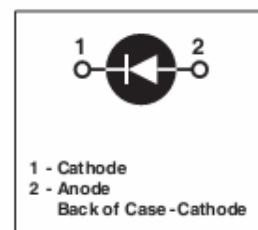
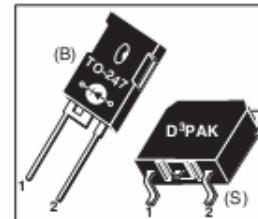
- Anti-Parallel Diode
 - Switchmode Power Supply
 - Inverters
- Free Wheeling Diode
 - Motor Controllers
 - Converters
 - Inverters
- Snubber Diode
- PFC

PRODUCT FEATURES

- Ultrafast Recovery Times
- Soft Recovery Characteristics
- Popular TO-247 Package or Surface Mount D³PAK Package
- Low Forward Voltage
- Low Leakage Current
- Avalanche Energy Rated

PRODUCT BENEFITS

- Low Losses
- Low Noise Switching
- Cooler Operation
- Higher Reliability Systems
- Increased System Power Density



MAXIMUM RATINGS

All Ratings: $T_C = 25^\circ\text{C}$ unless otherwise specified.

Symbol	Characteristic / Test Conditions	APT40DQ100B(G)_S(G)	UNIT
V_R	Maximum D.C. Reverse Voltage	1000	Volts
V_{RRM}	Maximum Peak Repetitive Reverse Voltage		
V_{RWM}	Maximum Working Peak Reverse Voltage		
$I_{F(AV)}$	Maximum Average Forward Current ($T_C = 106^\circ\text{C}$, Duty Cycle = 0.5)	40	Amps
$I_{F(RMS)}$	RMS Forward Current (Square wave, 50% duty)	60	
I_{FSM}	Non-Repetitive Forward Surge Current ($T_J = 45^\circ\text{C}$, 8.3ms)	210	$^\circ\text{C}$
E_{AVL}	Avalanche Energy (1A, 40mH)	20	
T_J, T_{STG}	Operating and Storage Temperature Range	-55 to 175	
T_L	Lead Temperature for 10 Sec.	300	

STATIC ELECTRICAL CHARACTERISTICS

Symbol	Characteristic / Test Conditions	MIN	TYP	MAX	UNIT
V_F	Forward Voltage	$I_F = 40\text{A}$		2.5	3.0
		$I_F = 80\text{A}$		3.08	Volts
		$I_F = 40\text{A}, T_J = 125^\circ\text{C}$		1.97	
I_{RM}	Maximum Reverse Leakage Current	$V_R = 1000\text{V}$		100	μA
		$V_R = 1000\text{V}, T_J = 125^\circ\text{C}$		500	
C_T	Junction Capacitance, $V_R = 200\text{V}$		28		pF

DYNAMIC CHARACTERISTICS

APT40DQ100B(G)_S(G)

Symbol	Characteristic	Test Conditions	MIN	TYP	MAX	UNIT
t_{rr}	Reverse Recovery Time $I_F = 1A, di_F/dt = -100A/\mu s, V_R = 30V, T_J = 25^\circ C$	$I_F = 40A, di_F/dt = -200A/\mu s$ $V_R = 667V, T_C = 25^\circ C$	-	25		ns
t_{rr}	Reverse Recovery Time		-	250		
Q_{rr}	Reverse Recovery Charge	$I_F = 40A, di_F/dt = -200A/\mu s$ $V_R = 667V, T_C = 25^\circ C$	-	415		nC
I_{RRM}	Maximum Reverse Recovery Current		-	4	-	Amps
t_{rr}	Reverse Recovery Time	$I_F = 40A, di_F/dt = -200A/\mu s$ $V_R = 667V, T_C = 125^\circ C$	-	315		ns
Q_{rr}	Reverse Recovery Charge		-	1650		nC
I_{RRM}	Maximum Reverse Recovery Current	$I_F = 40A, di_F/dt = -1000A/\mu s$ $V_R = 667V, T_C = 125^\circ C$	-	9	-	Amps
t_{rr}	Reverse Recovery Time		-	145		ns
Q_{rr}	Reverse Recovery Charge	$I_F = 40A, di_F/dt = -1000A/\mu s$ $V_R = 667V, T_C = 125^\circ C$	-	2660		nC
I_{RRM}	Maximum Reverse Recovery Current		-	29		Amps

THERMAL AND MECHANICAL CHARACTERISTICS

Symbol	Characteristic / Test Conditions	MIN	TYP	MAX	UNIT
R_{JC}	Junction-to-Case Thermal Resistance			.61	°C/W
W_T	Package Weight		0.22		oz
			5.9		g
Torque	Maximum Mounting Torque			10	lb•in
				1.1	N•m

APT Reserves the right to change, without notice, the specifications and information contained herein.

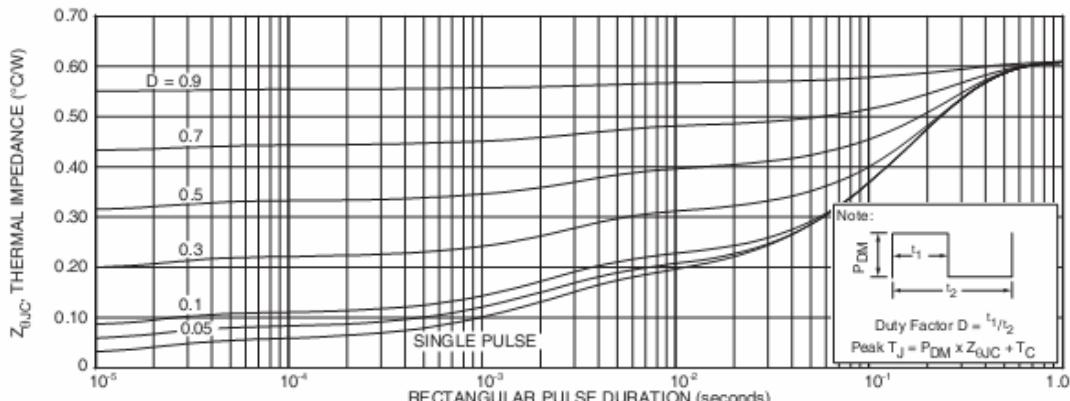


FIGURE 1a. MAXIMUM EFFECTIVE TRANSIENT THERMAL IMPEDANCE, JUNCTION-TO-CASE vs. PULSE DURATION

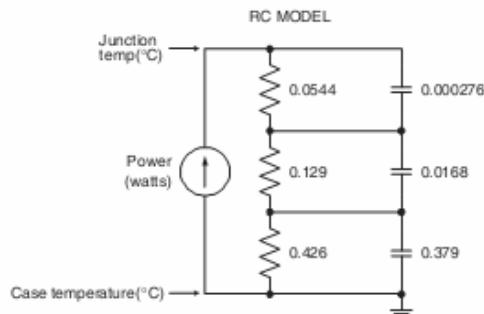


FIGURE 1b. TRANSIENT THERMAL IMPEDANCE MODEL

TYPICAL PERFORMANCE CURVES

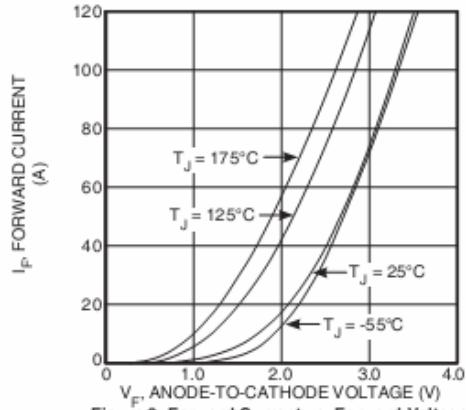


Figure 2. Forward Current vs. Forward Voltage

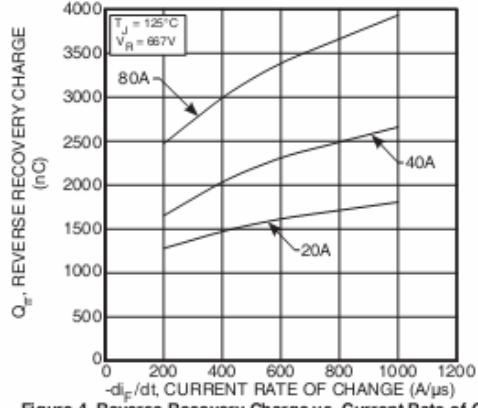


Figure 4. Reverse Recovery Charge vs. Current Rate of Change

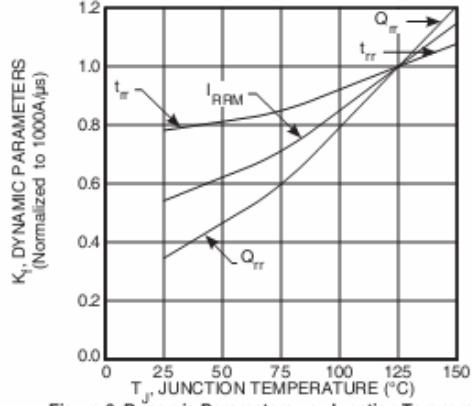


Figure 6. Dynamic Parameters vs. Junction Temperature

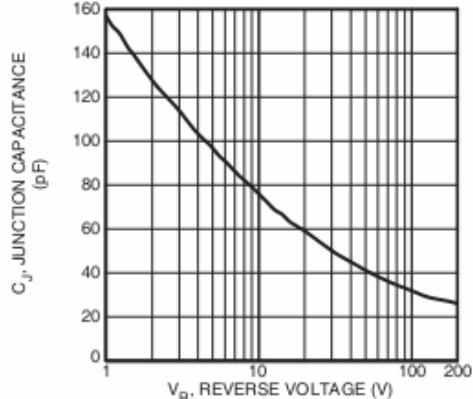


Figure 8. Junction Capacitance vs. Reverse Voltage

APT40DQ100B(G)_S(G)

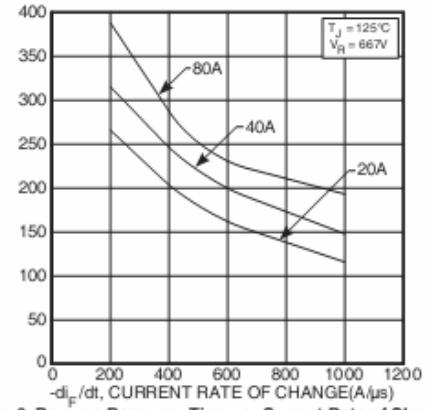


Figure 3. Reverse Recovery Time vs. Current Rate of Change

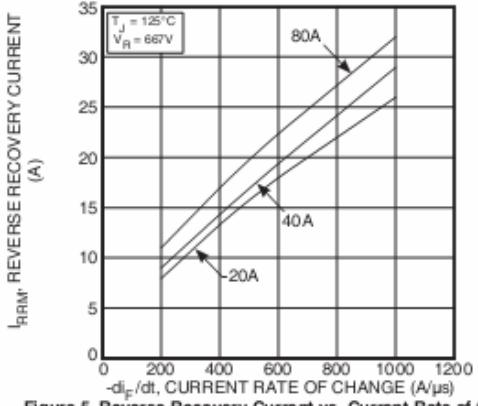


Figure 5. Reverse Recovery Current vs. Current Rate of Change

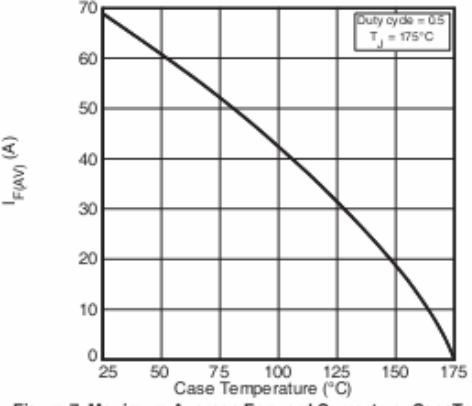


Figure 7. Maximum Average Forward Current vs. Case Temperature

APT40DQ100B(G)_S(G)

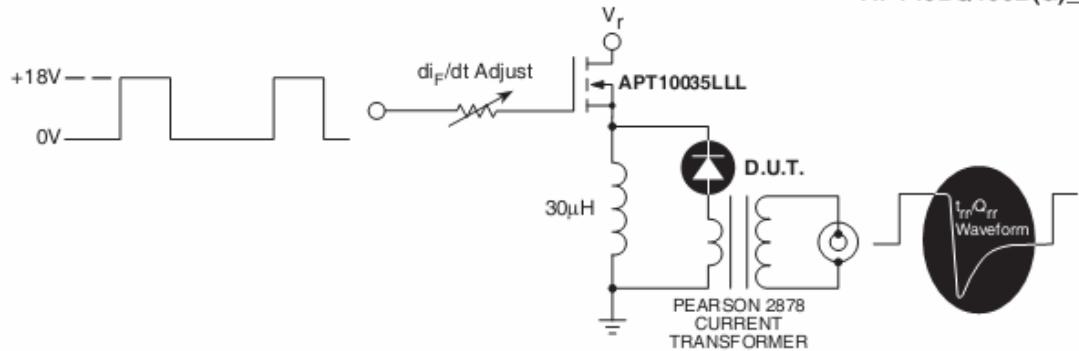


Figure 9. Diode Test Circuit

- 1 I_F - Forward Conduction Current
 - 2 dI_F/dt - Rate of Diode Current Change Through Zero Crossing.
 - 3 I_{RRM} - Maximum Reverse Recovery Current.
 - 4 t_{rr} - Reverse Recovery Time, measured from zero crossing where diode current goes from positive to negative, to the point at which the straight line through I_{RRM} and 0.25 * I_{RRM} passes through zero.
 - 5 Q_{rr} - Area Under the Curve Defined by I_{RRM} and t_{rr}.

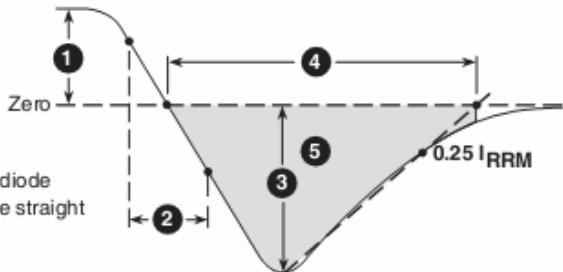
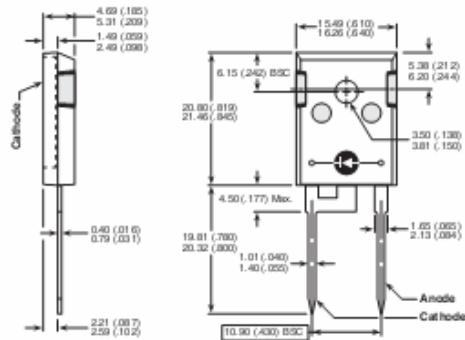


Figure 10, Diode Reverse Recovery Waveform and Definitions

TO-247 Package Outline

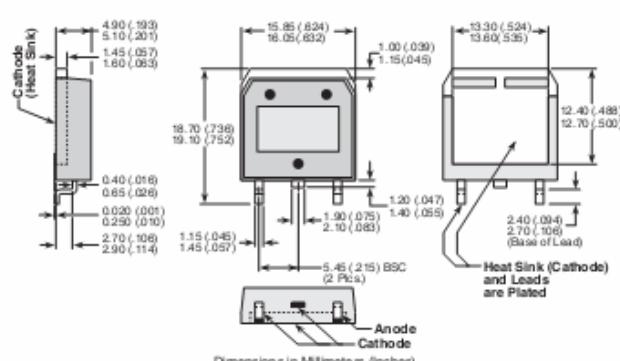
(e1) SAC: Tin, Silver, Copper



Dimensions in Millimeters and (Inches)

D³PAK Package Outline

e3 100% Sn



Dimensions in Millimeters (Inches)